## Notice of References Cited Application/Control No. 10/797,443 Examiner Kevin Y. Kim Applicant(s)/Patent Under Reexamination WEI, JASON Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0203559	10-2004	Stojanovic et al.	455/403
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## FOREIGN PATENT DOCUMENTS

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